

Armin Dadgar

List of Publications by Year in descending order

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250
papers

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times ranked

5459
citing authors

| # | ARTICLE | IF | CITATIONS |
|----|---|------|-----------|
| 1 | Metalorganic Chemical Vapor Phase Epitaxy of Crack-Free GaN on Si (111) Exceeding 1 μm in Thickness. Japanese Journal of Applied Physics, 2000, 39, L1183-L1185. | 1.5 | 310 |
| 2 | GaN-based optoelectronics on silicon substrates. Materials Science and Engineering B: Solid-State Materials for Advanced Technology, 2002, 93, 77-84. | 3.5 | 268 |
| 3 | Template-Assisted Large-Scale Ordered Arrays of ZnO Pillars for Optical and Piezoelectric Applications. Small, 2006, 2, 561-568. | 10.0 | 209 |
| 4 | Thick, crack-free blue light-emitting diodes on Si(111) using low-temperature AlN interlayers and in situ Si ₃ N ₄ masking. Applied Physics Letters, 2002, 80, 3670-3672. | 3.3 | 183 |
| 5 | Gallium nitride vertical power devices on foreign substrates: a review and outlook. Journal Physics D: Applied Physics, 2018, 51, 273001. | 2.8 | 173 |
| 6 | GaN-Based Devices on Si. Physica Status Solidi A, 2002, 194, 361-375. | 1.7 | 164 |
| 7 | High Si and Ge n-type doping of GaN doping - Limits and impact on stress. Applied Physics Letters, 2012, 100, . | 3.3 | 160 |
| 8 | Arrays of vertically aligned and hexagonally arranged ZnO nanowires: a new template-directed approach. Nanotechnology, 2005, 16, 913-917. | 2.6 | 147 |
| 9 | High-sheet-charge carrier-density AlInN-GaN field-effect transistors on Si(111). Applied Physics Letters, 2004, 85, 5400-5402. | 3.3 | 133 |
| 10 | Band gap renormalization and Burstein-Moss effect in silicon- and germanium-doped wurtzite GaN up to 10^{20} cm^{-3} . Physical Review B, 2014, 90, . | 3.2 | 133 |
| 11 | MOVPE growth of GaN on Si(111) substrates. Journal of Crystal Growth, 2003, 248, 556-562. | 1.5 | 125 |
| 12 | GaN-based epitaxy on silicon: stress measurements. Physica Status Solidi A, 2003, 200, 26-35. | 1.7 | 125 |
| 13 | Epitaxy of GaN on silicon – impact of symmetry and surface reconstruction. New Journal of Physics, 2007, 9, 389-389. | 2.9 | 124 |
| 14 | Metal-organic vapor phase epitaxy and properties of AlInN in the whole compositional range. Applied Physics Letters, 2007, 90, 022105. | 3.3 | 119 |
| 15 | The origin of stress reduction by low-temperature AlN interlayers. Applied Physics Letters, 2002, 81, 2722-2724. | 3.3 | 117 |
| 16 | Efficient stress relief in GaN heteroepitaxy on Si(111) using low-temperature AlN interlayers. Journal of Crystal Growth, 2003, 248, 563-567. | 1.5 | 117 |
| 17 | Growth of blue GaN LED structures on 150-mm Si(111). Journal of Crystal Growth, 2006, 297, 279-282. | 1.5 | 117 |
| 18 | Metalorganic chemical vapor phase epitaxy of gallium-nitride on silicon. Physica Status Solidi C: Current Topics in Solid State Physics, 2003, 0, 1583-1606. | 0.8 | 116 |

| # | ARTICLE | IF | CITATIONS |
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| 19 | Atomic arrangement at the AlN/Si (111) interface. Applied Physics Letters, 2003, 83, 860-862. | 3.3 | 114 |
| 20 | Piezoelectric GaN sensor structures. IEEE Electron Device Letters, 2006, 27, 309-312. | 3.9 | 113 |
| 21 | Recording of cell action potentials with AlGaIn/GaN field-effect transistors. Applied Physics Letters, 2005, 86, 033901. | 3.3 | 112 |
| 22 | Dislocation annihilation by silicon delta-doping in GaN epitaxy on Si. Applied Physics Letters, 2002, 81, 4712-4714. | 3.3 | 109 |
| 23 | Well-ordered ZnO nanowire arrays on GaN substrate fabricated via nanosphere lithography. Journal of Crystal Growth, 2006, 287, 34-38. | 1.5 | 108 |
| 24 | Bright blue electroluminescence from an InGaIn/GaN multiquantum-well diode on Si(111): Impact of an AlGaIn/GaN multilayer. Applied Physics Letters, 2001, 78, 2211-2213. | 3.3 | 106 |
| 25 | Reduction of stress at the initial stages of GaN growth on Si(111). Applied Physics Letters, 2003, 82, 28-30. | 3.3 | 102 |
| 26 | Vapour-transport-deposition growth of ZnO nanostructures: switch between c-axis wires and a-axis belts by indium doping. Nanotechnology, 2006, 17, S231-S239. | 2.6 | 97 |
| 27 | Laser-Interference Lithography Tailored for Highly Symmetrically Arranged ZnO Nanowire Arrays. Small, 2007, 3, 76-80. | 10.0 | 95 |
| 28 | Fabrication, Self-Assembly, and Properties of Ultrathin AlN/GaN Porous Crystalline Nanomembranes: Tubes, Spirals, and Curved Sheets. ACS Nano, 2009, 3, 1663-1668. | 14.6 | 91 |
| 29 | Local p-type conductivity in zinc oxide dual-doped with nitrogen and arsenic. Applied Physics Letters, 2005, 87, 262105. | 3.3 | 90 |
| 30 | Two charge states of the C_N acceptor in GaN: Evidence from photoluminescence. Physical Review B, 2018, 98, . | 3.2 | 84 |
| 31 | MOVPE growth of GaN on Si " Substrates and strain. Thin Solid Films, 2007, 515, 4356-4361. | 1.8 | 81 |
| 32 | Transient Thermal Characterization of AlGaIn/GaN HEMTs Grown on Silicon. IEEE Transactions on Electron Devices, 2005, 52, 1698-1705. | 3.0 | 78 |
| 33 | Sixteen years GaN on Si. Physica Status Solidi (B): Basic Research, 2015, 252, 1063-1068. | 1.5 | 76 |
| 34 | Crack-Free, Highly Conducting GaN Layers on Si Substrates by Ge Doping. Applied Physics Express, 2011, 4, 011001. | 2.4 | 73 |
| 35 | Patterned growth of aligned ZnO nanowire arrays on sapphire and GaN layers. Superlattices and Microstructures, 2004, 36, 95-105. | 3.1 | 70 |
| 36 | High-Performance 500 V Quasi- and Fully-Vertical GaN-on-Si pn Diodes. IEEE Electron Device Letters, 2017, 38, 248-251. | 3.9 | 70 |

| # | ARTICLE | IF | CITATIONS |
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| 37 | Fabry-Perot effects in InGaN ^x GaN heterostructures on Si-substrate. Journal of Applied Physics, 2007, 101, 033113. | 2.5 | 69 |
| 38 | MOVPE growth of high-quality AlN. Journal of Crystal Growth, 2006, 297, 306-310. | 1.5 | 68 |
| 39 | Dielectric function and optical properties of Al-rich AlInN alloys pseudomorphically grown on GaN. Journal Physics D: Applied Physics, 2010, 43, 365102. | 2.8 | 66 |
| 40 | P-Channel InGaN-HFET Structure Based on Polarization Doping. IEEE Electron Device Letters, 2004, 25, 450-452. | 3.9 | 62 |
| 41 | Improving GaN ^x Si properties for GaN device epitaxy. Physica Status Solidi C: Current Topics in Solid State Physics, 2011, 8, 1503-1508. | 0.8 | 59 |
| 42 | All metalorganic chemical vapor phase epitaxy of p/n-GaN tunnel junction for blue light emitting diode applications. Applied Physics Letters, 2017, 110, . | 3.3 | 59 |
| 43 | Thermal stability of metal organic vapor phase epitaxy grown AlInN. Applied Physics Letters, 2007, 90, 221906. | 3.3 | 53 |
| 44 | Self-assembly of ZnO nanowires and the spatial resolved characterization of their luminescence. Nanotechnology, 2004, 15, 1401-1404. | 2.6 | 52 |
| 45 | A two-step metal organic vapor phase epitaxy growth method for high-quality ZnO on GaN/Al ₂ O ₃ (0001). Journal of Crystal Growth, 2004, 267, 140-144. | 1.5 | 52 |
| 46 | Crack-Free InGaN/GaN Light Emitters on Si(111). Physica Status Solidi A, 2001, 188, 155-158. | 1.7 | 48 |
| 47 | Decoration effects as origin of dislocation-related charges in gallium nitride layers investigated by scanning surface potential microscopy. Applied Physics Letters, 2003, 82, 2263-2265. | 3.3 | 48 |
| 48 | Metalorganic chemical vapor phase deposition of ZnO with different O-precursors. Journal of Crystal Growth, 2003, 248, 14-19. | 1.5 | 46 |
| 49 | Influence of buffer layers on metalorganic vapor phase epitaxy grown GaN on Si(001). Applied Physics Letters, 2004, 84, 4747-4749. | 3.3 | 46 |
| 50 | Influence of exciton-phonon coupling and strain on the anisotropic optical response of wurtzite AlN around the band edge. Physical Review B, 2011, 83, . | 3.2 | 46 |
| 51 | UNSTRAINED InAlN/GaN HEMT STRUCTURE. International Journal of High Speed Electronics and Systems, 2004, 14, 785-790. | 0.7 | 42 |
| 52 | Metalorganic vapor phase epitaxy grown InGaN ^x GaN light-emitting diodes on Si(001) substrate. Applied Physics Letters, 2006, 88, 121114. | 3.3 | 42 |
| 53 | Bright, Crack-Free InGaN/GaN Light Emitters on Si(111). Physica Status Solidi A, 2002, 192, 308-313. | 1.7 | 41 |
| 54 | In situ measurements of strains and stresses in GaN heteroepitaxy and its impact on growth temperature. Journal of Crystal Growth, 2004, 272, 72-75. | 1.5 | 41 |

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| 55 | In situ monitoring of the stress evolution in growing group-III-nitride layers. Journal of Crystal Growth, 2005, 275, 209-216. | 1.5 | 40 |
| 56 | Germanium - the superior dopant in n-type GaN. Physica Status Solidi - Rapid Research Letters, 2015, 9, 716-721. | 2.4 | 40 |
| 57 | Ostwald ripening and flattening of epitaxial ZnO layers during in situ annealing in metalorganic vapor phase epitaxy. Applied Physics Letters, 2004, 85, 1496-1498. | 3.3 | 39 |
| 58 | Reduction of on-resistance and current crowding in quasi-vertical GaN power diodes. Applied Physics Letters, 2017, 111, . | 3.3 | 39 |
| 59 | Evolution of stress in GaN heteroepitaxy on AlN [∧] Si(111): From hydrostatic compressive to biaxial tensile. Applied Physics Letters, 2004, 85, 3441-3443. | 3.3 | 38 |
| 60 | Homoepitaxial growth of ZnO by metalorganic vapor phase epitaxy in two-dimensional growth mode. Journal of Crystal Growth, 2007, 308, 170-175. | 1.5 | 37 |
| 61 | High-current AlInN/GaN field effect transistors. Physica Status Solidi (A) Applications and Materials Science, 2005, 202, 832-836. | 1.8 | 36 |
| 62 | Two-dimensional electron gas based actuation of piezoelectric AlGaIn/GaN microelectromechanical resonators. Applied Physics Letters, 2008, 93, . | 3.3 | 36 |
| 63 | Role of low-temperature AlGaIn interlayers in thick GaN on silicon by metalorganic vapor phase epitaxy. Journal of Applied Physics, 2012, 111, . | 2.5 | 36 |
| 64 | InGaIn/GaN light-emitting diodes on Si(1 [∧] %0) substrates grown by metal [∧] organic vapour phase epitaxy. Journal Physics D: Applied Physics, 2009, 42, 055107. | 2.8 | 35 |
| 65 | In Ga N [∧] Ga N light emitting diodes on nanoscale silicon on insulator. Applied Physics Letters, 2007, 91, . | 3.3 | 34 |
| 66 | Optical and structural microanalysis of GaN grown on SiN submonolayers. Journal of Applied Physics, 2006, 99, 123518. | 2.5 | 33 |
| 67 | Growth of single-domain GaN layers on Si(001) by metalorganic vapor-phase epitaxy. Journal of Crystal Growth, 2006, 289, 485-488. | 1.5 | 33 |
| 68 | Anisotropy of effective electron masses in highly doped nonpolar GaN. Applied Physics Letters, 2013, 103, . | 3.3 | 33 |
| 69 | Properties of C [∧] doped GaN. Physica Status Solidi (B): Basic Research, 2017, 254, 1600708. | 1.5 | 33 |
| 70 | Ruthenium: A superior compensator of InP. Applied Physics Letters, 1998, 73, 3878-3880. | 3.3 | 32 |
| 71 | Complex excitonic recombination kinetics in ZnO: Capture, relaxation, and recombination from steady state. Applied Physics Letters, 2007, 90, 041917. | 3.3 | 31 |
| 72 | Methodology for the investigation of threading dislocations as a source of vertical leakage in AlGaIn/GaN-HEMT heterostructures for power devices. Journal of Applied Physics, 2019, 125, . | 2.5 | 30 |

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| 73 | Direct evidence of single quantum dot emission from GaN islands formed at threading dislocations using nanoscale cathodoluminescence: A source of single photons in the ultraviolet. Applied Physics Letters, 2015, 106, . | 3.3 | 29 |
| 74 | Analysis of point defects in AlN epilayers by cathodoluminescence spectroscopy. Applied Physics Letters, 2009, 95, . | 3.3 | 28 |
| 75 | ZnO MOVPE growth: From local impurity incorporation towards p-type doping. Superlattices and Microstructures, 2005, 38, 245-255. | 3.1 | 27 |
| 76 | Metal organic vapor phase epitaxy growth of single crystalline GaN on planar Si(211) substrates. Applied Physics Letters, 2009, 95, . | 3.3 | 27 |
| 77 | Valence-band splitting and optical anisotropy of AlN. Physica Status Solidi (B): Basic Research, 2010, 247, 1679-1682. | 1.5 | 26 |
| 78 | On reduction of current leakage in GaN by carbon-doping. Applied Physics Letters, 2016, 109, . | 3.3 | 25 |
| 79 | GaN micromachined FBAR structures for microwave applications. Superlattices and Microstructures, 2006, 40, 426-431. | 3.1 | 24 |
| 80 | Metal Organic Vapor Phase Epitaxy of ZnO on GaN/Si(111) Using Tertiary-Butanol as O-Precursor. Japanese Journal of Applied Physics, 2003, 42, 7474-7477. | 1.5 | 23 |
| 81 | Wafer curvature in the nonlinear deformation range. Physica Status Solidi A, 2004, 201, R75-R78. | 1.7 | 23 |
| 82 | Modulation spectroscopy of AlGaIn/GaN heterostructures: The influence of electron-hole interaction. Physica Status Solidi (A) Applications and Materials Science, 2007, 204, 447-458. | 1.8 | 23 |
| 83 | Leakage currents and Fermi-level shifts in GaN layers upon iron and carbon-doping. Journal of Applied Physics, 2017, 122, . | 2.5 | 23 |
| 84 | Influence of excitons and electric fields on the dielectric function of GaN: Theory and experiment. Physical Review B, 2006, 74, . | 3.2 | 22 |
| 85 | Epitaxy of GaN LEDs on large substrates: Si or sapphire?. , 2006, , . | | 22 |
| 86 | Semipolar single component GaN on planar high index Si(11h) substrates. Applied Physics Letters, 2010, 97, . | 3.3 | 22 |
| 87 | Eliminating stacking faults in semi-polar GaN by AlN interlayers. Applied Physics Letters, 2011, 99, 021905. | 3.3 | 22 |
| 88 | Growth of AlInN/GaN distributed Bragg reflectors with improved interface quality. Journal of Crystal Growth, 2015, 414, 105-109. | 1.5 | 22 |
| 89 | Atomic Arrangement at the AlN/Si(110) Interface. Applied Physics Express, 0, 1, 061104. | 2.4 | 21 |
| 90 | Strain evaluation in AlInN/GaN Bragg mirrors by <i>in situ</i> curvature measurements and <i>ex situ</i> x-ray grazing incidence and transmission scattering. Applied Physics Letters, 2010, 97, . | 3.3 | 21 |

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| 91 | Low-temperature/high-temperature AlN superlattice buffer layers for high-quality Al _x Ga _{1-x} N on Si (111). Journal of Crystal Growth, 2009, 311, 3742-3748. | 1.5 | 20 |
| 92 | InAlN/GaN/Si heterostructures and field-effect transistors with lattice matched and tensely or compressively strained InAlN. Applied Physics Letters, 2010, 97, 173505. | 3.3 | 19 |
| 93 | Reliable GaN-Based THz Gunn Diodes With Side-Contact and Field-Plate Technologies. IEEE Access, 2020, 8, 84116-84122. | 4.2 | 19 |
| 94 | Gallium-nitride-based devices on silicon. Physica Status Solidi C: Current Topics in Solid State Physics, 2003, 0, 1940-1949. | 0.8 | 18 |
| 95 | In-situ growth monitoring of AlInN/AlGaIn distributed Bragg reflectors for the UV-spectral range. Journal of Crystal Growth, 2013, 370, 87-91. | 1.5 | 18 |
| 96 | Ge as a surfactant in metal-organic vapor phase epitaxy growth of a-plane GaN exceeding carrier concentrations of 10 ²⁰ cm ⁻³ . Applied Physics Letters, 2013, 103, . | 3.3 | 18 |
| 97 | Capacitance transient study of the deep Fe acceptor in indium phosphide. Physical Review B, 1997, 56, 10241-10248. | 3.2 | 17 |
| 98 | Growth of Ru doped semi-insulating InP by low pressure metalorganic chemical vapor deposition. Journal of Crystal Growth, 1998, 195, 69-73. | 1.5 | 17 |
| 99 | Electrical microcharacterization of dislocation-related charges in GaN-based single layers by scanning probe microscopy techniques. Journal of Crystal Growth, 2003, 248, 542-547. | 1.5 | 17 |
| 100 | Time-delayed indium incorporation in ultrathin (In _x Ga _{1-x} N/GaN) multiple quantum wells grown by metalorganic vapor phase epitaxy. Applied Physics Letters, 2003, 82, 4558-4560. | 3.3 | 17 |
| 101 | A low-temperature evaporation route for ZnO nanoneedles and nanosaws. Applied Physics A: Materials Science and Processing, 2005, 80, 457-460. | 2.3 | 17 |
| 102 | Metalorganic vapor-phase epitaxy of GaN layers on Si substrates with Si(110) and other high-index surfaces. Journal of Crystal Growth, 2010, 312, 180-184. | 1.5 | 17 |
| 103 | Heavy Si doping: The key in heteroepitaxial growth of a-plane GaN without basal plane stacking faults?. Physica Status Solidi (B): Basic Research, 2011, 248, 578-582. | 1.5 | 17 |
| 104 | Phonons and free-carrier properties of binary, ternary, and quaternary group-III nitride layers measured by Infrared Spectroscopic Ellipsometry. Physica Status Solidi C: Current Topics in Solid State Physics, 2003, 0, 1750-1769. | 0.8 | 16 |
| 105 | Heteroepitaxy and nitrogen doping of high-quality ZnO. Journal of Crystal Growth, 2004, 272, 800-804. | 1.5 | 16 |
| 106 | GaN heteroepitaxy on Si(001). Journal of Crystal Growth, 2004, 272, 496-499. | 1.5 | 16 |
| 107 | Electroreflectance spectroscopy of Pt _{1-x} AlGa _x N _{1-x} GaN heterostructures exposed to gaseous hydrogen. Applied Physics Letters, 2006, 88, 024101. | 3.3 | 16 |
| 108 | Temperature rise in InGaIn/GaN vertical light emitting diode on copper transferred from silicon probed by Raman scattering. Journal of Applied Physics, 2010, 108, . | 2.5 | 16 |

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| 109 | Growth and stacking fault reduction in semi-polar GaN films on planar Si(112) and Si(113). <i>Physica Status Solidi C: Current Topics in Solid State Physics</i> , 2012, 9, 507-510. | 0.8 | 16 |
| 110 | Breakdown of Far-Field Raman Selection Rules by Light-Plasmon Coupling Demonstrated by Tip-Enhanced Raman Scattering. <i>Journal of Physical Chemistry Letters</i> , 2017, 8, 5462-5471. | 4.6 | 16 |
| 111 | Bright blue to orange photoluminescence emission from high-quality InGaN/GaN multiple-quantum-wells on Si(111) substrates. <i>Applied Physics Letters</i> , 2002, 81, 1591-1593. | 3.3 | 15 |
| 112 | Growth of ZnO Layers by Metal Organic Chemical Vapor Phase Epitaxy. <i>Physica Status Solidi A</i> , 2002, 192, 189-194. | 1.7 | 15 |
| 113 | Thin-film InGa ^x N ^{1-x} -GaN Vertical Light Emitting Diodes Using GaN on Silicon-On-Insulator Substrates. <i>Electrochemical and Solid-State Letters</i> , 2011, 14, H460. | 2.2 | 15 |
| 114 | MOVPE growth of semi-polar GaN light-emitting diode structures on planar Si(112) and Si(113) substrates. <i>Journal of Crystal Growth</i> , 2013, 370, 288-292. | 1.5 | 15 |
| 115 | Deep-level transient-spectroscopy study of rhodium in indium phosphide. <i>Physical Review B</i> , 1996, 53, 7190-7196. | 3.2 | 14 |
| 116 | Surface stability of InGaN-channel based HFETs. <i>Electronics Letters</i> , 2003, 39, 1614. | 1.0 | 14 |
| 117 | Anisotropic bow and plastic deformation of GaN on silicon. <i>Journal of Crystal Growth</i> , 2013, 370, 278-281. | 1.5 | 14 |
| 118 | Direct evidence for selective impurity incorporation at the crystal domain boundaries in epitaxial ZnO layers. <i>Applied Physics Letters</i> , 2004, 85, 1976-1978. | 3.3 | 13 |
| 119 | Depth-resolving structural analysis of GaN layers by skew angle x-ray diffraction. <i>Applied Physics Letters</i> , 2004, 84, 3537-3539. | 3.3 | 13 |
| 120 | Simultaneous measurement of wafer curvature and true temperature during metalorganic growth of group-III nitrides on silicon and sapphire. <i>Physica Status Solidi (B): Basic Research</i> , 2005, 242, 2570-2574. | 1.5 | 13 |
| 121 | Green to blue polarization compensated c-axis oriented multi-quantum wells by AlGaInN barrier layers. <i>Applied Physics Letters</i> , 2013, 102, . | 3.3 | 13 |
| 122 | Thermal stability of the midgap acceptor rhodium in indium phosphide. <i>Applied Physics Letters</i> , 1995, 67, 479-481. | 3.3 | 12 |
| 123 | Temperature dependence of the built-in electric field strength of AlGaIn/GaN heterostructures on Si(111) substrate. <i>Superlattices and Microstructures</i> , 2004, 36, 693-700. | 3.1 | 12 |
| 124 | Crystallographic and electric properties of MOVPE-grown AlGaIn/GaN-based FETs on Si(001) substrates. <i>Journal of Crystal Growth</i> , 2007, 299, 399-403. | 1.5 | 12 |
| 125 | Microstructural anisotropy of c-plane GaN analyzed by high resolution X-ray diffraction. <i>Physica Status Solidi C: Current Topics in Solid State Physics</i> , 2009, 6, S498. | 0.8 | 12 |
| 126 | Cathodoluminescence of epitaxial GaN and ZnO thin films for scintillator applications. <i>Journal of Crystal Growth</i> , 2009, 311, 3984-3988. | 1.5 | 12 |

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| 127 | Microstructure of gallium nitride films grown on silicon (110). Applied Physics Letters, 2010, 96, 231908. | 3.3 | 12 |
| 128 | Luminescence from two-dimensional electron gases in InAlN/GaN heterostructures with different In content. Applied Physics Letters, 2012, 100, . | 3.3 | 12 |
| 129 | Growth and characterization of stacking fault reduced GaN $(1,0,ar\{1,3\})$ on sapphire. Journal Physics D: Applied Physics, 2013, 46, 125308. | 2.8 | 12 |
| 130 | Local p-type conductivity in n-GaN and n-ZnO layers due to inhomogeneous dopant incorporation. Physica B: Condensed Matter, 2006, 376-377, 703-706. | 2.7 | 11 |
| 131 | AllnN/GaN based multi quantum well structures â€“ growth and optical properties. Physica Status Solidi C: Current Topics in Solid State Physics, 2009, 6, S451. | 0.8 | 11 |
| 132 | Growth of AllnN/AlGaN distributed Bragg reflectors for high quality microcavities. Physica Status Solidi C: Current Topics in Solid State Physics, 2012, 9, 1253-1258. | 0.8 | 11 |
| 133 | Metalorganic chemical vapor phase epitaxy of narrow-band distributed Bragg reflectors realized by GaN:Ge modulation doping. Journal of Crystal Growth, 2016, 440, 6-12. | 1.5 | 11 |
| 134 | Radiation-induced alloy rearrangement in In<i>x</i>Ga1â”<i>x</i>N. Applied Physics Letters, 2017, 110, . | 3.3 | 11 |
| 135 | Highâ€resolution xâ€ray analysis of compressively strained 1.55 Î¼m GaInAs/AlGaInAs multiquantum well structures near the critical thickness. Applied Physics Letters, 1995, 67, 3325-3327. | 3.3 | 10 |
| 136 | MOVPE Growth and Characterization of AllnN FET Structures on Si(111). Materials Research Society Symposia Proceedings, 2008, 1068, 1. | 0.1 | 10 |
| 137 | Influence of anisotropic strain on excitonic transitions in a-plane GaN films. Microelectronics Journal, 2009, 40, 322-324. | 2.0 | 10 |
| 138 | Valence band tomography of wurtzite GaN by spectroscopic ellipsometry. Applied Physics Express, 2018, 11, 101001. | 2.4 | 10 |
| 139 | Metalorganic vapor phase epitaxy of ZnO: towards p-type conductivity. , 2007, 6474, 32. | | 9 |
| 140 | Electrical investigations of AlGaN/AlN structures for LEDs on Si(111). Physica Status Solidi (A) Applications and Materials Science, 2011, 208, 1597-1599. | 1.8 | 9 |
| 141 | Flexible Modulation of Electronic Band Structures of Wide Band Gap GaN Semiconductors Using Bioinspired, Nonbiological Helical Peptides. Advanced Functional Materials, 2018, 28, 1704034. | 14.9 | 9 |
| 142 | Strain profiling of AllnN/GaN distributed Bragg reflectors using in situ curvature measurements and ex situ X-ray diffraction. Materials Science & Engineering A: Structural Materials: Properties, Microstructure and Processing, 2010, 528, 58-64. | 5.6 | 8 |
| 143 | Growth of III/Vs on Silicon. , 2015, , 1249-1300. | | 8 |
| 144 | Novel ways to grow thermally stable semi-insulating InP-based layers. Journal of Crystal Growth, 1994, 145, 455-461. | 1.5 | 7 |

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| 145 | Characterization of defects in undoped non c-plane and high resistance GaN layers dominated by stacking faults. <i>Physica B: Condensed Matter</i> , 2009, 404, 4922-4924. | 2.7 | 7 |
| 146 | 4d- and 5d-transition metal acceptor doping of InP. <i>Journal of Crystal Growth</i> , 1997, 170, 173-176. | 1.5 | 6 |
| 147 | Characteristics of Alpha-Radiation-Induced Deep Level Defects in p-Type InP Grown by Metal-Organic Chemical Vapor Deposition. <i>Japanese Journal of Applied Physics</i> , 1998, 37, 4595-4602. | 1.5 | 6 |
| 148 | Unstrained InAlN/GaN HEMT structure. , 0, , . | | 6 |
| 149 | Correlation between macroscopic transport parameters and microscopic electrical properties in GaN. <i>Journal of Applied Physics</i> , 2005, 97, 043710. | 2.5 | 6 |
| 150 | Monitoring glycolytic oscillations using AlGaIn/GaN high electron mobility transistors (HEMTs). <i>Sensors and Actuators B: Chemical</i> , 2010, 149, 310-313. | 7.8 | 6 |
| 151 | Light extraction from GaN-based LED structures on silicon-on-insulator substrates. <i>Physica Status Solidi C: Current Topics in Solid State Physics</i> , 2010, 7, 88-91. | 0.8 | 6 |
| 152 | Luminescence Properties of Photonic Crystal InGaIn/GaN Light Emitting Layers on Silicon-on-Insulator. <i>Electrochemical and Solid-State Letters</i> , 2010, 13, H343. | 2.2 | 6 |
| 153 | Direct microscopic correlation of crystal orientation and luminescence in spontaneously formed nonpolar and semipolar GaN growth domains. <i>Applied Physics Letters</i> , 2010, 96, . | 3.3 | 6 |
| 154 | Al _x Ga _{1-x} N/GaN heterostructures on a thin silicon-on-insulator substrate for metal-semiconductor-metal photodetectors. <i>Journal Physics D: Applied Physics</i> , 2011, 44, 365102. | 2.8 | 6 |
| 155 | Impact of AlN seeding layer growth rate in MOVPE growth of semi-polar gallium nitride structures on high index silicon. <i>Physica Status Solidi (B): Basic Research</i> , 2011, 248, 594-599. | 1.5 | 6 |
| 156 | Characterization of AlGaInN layers using X-ray diffraction and fluorescence. <i>Physica Status Solidi (B): Basic Research</i> , 2011, 248, 622-626. | 1.5 | 6 |
| 157 | Wafer curvature, temperature inhomogeneity, plastic deformation and their impact on the properties of GaN on silicon power and optoelectronic structures. <i>Physica Status Solidi C: Current Topics in Solid State Physics</i> , 2014, 11, 397-400. | 0.8 | 6 |
| 158 | Characterization of AlInN/AlN/GaN FET structures using x-ray diffraction, x-ray reflectometry and grazing incidence x-ray fluorescence analysis. <i>Journal Physics D: Applied Physics</i> , 2014, 47, 355106. | 2.8 | 6 |
| 159 | Polarization engineering of c-plane InGaIn quantum wells by pulsed-flow growth of AlInGaIn barriers. <i>Physica Status Solidi (B): Basic Research</i> , 2016, 253, 118-125. | 1.5 | 6 |
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